Search Notes	

_	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/720,348	TAKEUCHI ET AL.	
	Examiner	Art Unit	
	Amy P. Cohon	2850	

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Class	Subclass	Date	Examiner
33	264 355R 356	7/6/2004	ARC
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Updated		6/23/2005	ARC
33	357		
Updated		12/5/2005	ARC

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